

(In collaboration with JEOL Ltd.)

specially invites you to a seminar demonstrating our new

Scanning Electron Microscope (SEM) with Nano-Analysis capabilities

PRESENTERS:

Mr. Riza Khan

VP - In-Corr-Tech Ltd.

Mr. Robert Westby

Regional Sales Manager - Jeol Ltd, USA

Mr. Terry McNeese

Applications Engineer - Jeol Ltd, USA


Date: Friday October 26th, 2018
Time: 1:00 pm - 5:00 pm
Venue: In-Corr-Tech Ltd's Facility,
Rodriguez Ave, 15 Ciperro Road, San Fernando

Special applications include:

- ◆ Root Cause Analysis / Failure Analysis
- ◆ Gunshot Residue, Ballistics & Forensics
- ◆ Food & Pharmaceutical Drugs (Counterfeit drug detection)
- ◆ Illicit Drug Detection
- ◆ Research & Development (Universities, Schools, Technical Institutes)
- ◆ Surface Chemistry and Contaminant Analyses

Includes hands-on demonstration with the instrument!

Attendance by invitation only.

 (868) 652-4638/1208/6155/7675

 training@incorrttech.com

